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Advanced Sensing and Machine Learning Techniques in Process Monitoring and Fault Diagnosis

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Message from the Guest Editors

Dear Colleagues,

Over the past few decades, machine learning and artificial intelligence (ML/AI) techniques, such as the emerging deep learning methods, have attracted much attention in computer-based advanced manufacturing and prognostic and health management. A comprehensive information physical system based on advanced sensing and machine learning, however, is still missing in advanced manufacturing and fault diagnosis. Developing such a comprehensive diagnostics system requires novel developments related to intelligent information physical systems, advanced sensing techniques, deep analysis and sensor fusion, adaptability of artificial intelligence technology to complex environments, and specific working conditions.













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Message from the Editor-in-Chief

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